ON Semiconductor



Final Product/Process Change Notification Document # : FPCN21451X

Issue Date: 13 September 2016

Title of Change:	Transfer of DSN2 Schottky plating site from existing external foundry facility to existing internal manufacturing site in Niigata, Japan.		
Proposed first ship date:	20 December 2016 or earlier upon customer approval		
Contact information:	Contact your local ON Semiconductor Sales Office or <masitah.aznam@onsemi.com></masitah.aznam@onsemi.com>		
Samples:	Contact your local ON Semiconductor Sales Office or <masitah.aznam@onsemi.com></masitah.aznam@onsemi.com>		
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <masitah.aznam@onsemi.com></masitah.aznam@onsemi.com>		
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change.		
	ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>		
	Affected products from these changes with date code Dec 2016 and greater may be sourced from ON Niigata plating (Japan). Products from new sites will be identified through updated marking format as shown below.		
	NSR05F30NXT5G NSR05F30NXT5G Existing marking New marking		
Change Part Identification:	$ \begin{array}{c} \begin{array}{c} \begin{array}{c} \begin{array}{c} \begin{array}{c} \end{array}\\ \end{array}\\ \end{array} \\ \begin{array}{c} \end{array}\\ \begin{array}{c} \end{array}\\ \end{array} \\ \begin{array}{c} \end{array}\\ \end{array} \\ \begin{array}{c} \end{array}\\ \begin{array}{c} \end{array}\\ \end{array} \\ \begin{array}{c} \end{array}\\ \end{array} \\ \begin{array}{c} \end{array}\\ \begin{array}{c} \end{array}\\ \end{array} \\ \begin{array}{c} \end{array}\\ \begin{array}{c} \end{array}\\ \end{array} \\ \begin{array}{c} \end{array}\\ \end{array} \\ \begin{array}{c} \end{array}\\ \begin{array}{c} \end{array}\\ \end{array} \\ \end{array} \\ \begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \begin{array}{c} \end{array} \\ \end{array} \\ \begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \end{array} $ \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \end{array} \\ \end{array} \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \end{array} \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \end{array} \\ \end{array} \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \end{array} \\ \end{array} \\ \end{array} \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \bigg \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \left\begin{array}{c} \end{array} \\ \end{array} \bigg \bigg \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \\ \end{array} } \\ \end{array} \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \left\begin{array}{c} \end{array} \\ \end{array} \\ \end{array} \left \end{array} \\ \end{array} \left \end{array} \\ \end{array} \left \end{array} \\ \end{array} T T T T T T T T T T T T T T T T T T		
Change category:	Wafer Fab Change Assembly Change X Test Change Other Plating Change		
Change Sub-Category(s): Manufacturing Site Change/ Manufacturing Process Char Sites Affected:			
	oplicable Image: Construction of the state of the		
Description and Purpose: This Final Notification announces to customers of its plans to transfer of DSN2 Schottky plating site from existing external foundry facility to existing internal manufacturing site in Niigata, Japan. ON Niigata facility is ON Semiconductor owned site that have been producing products for ON Semiconductor. Several existing technologies within ON Semiconductor's product families are currently sourced from both sites. ON Niigata is internal factory sites that are TS16949, ISO-9001			

Qualification tests are designed to show that the reliability of the transferred devices will continue to meet or exceed ON Semiconductor standards.

and ISO-14000 certified.



Reliability Data Summary:

QV DEVICE NAME : NSR10F40NXT5G

PACKAGE: DSN2

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=90°C, 80% max rated V	1008 hrs	0/240
TC	JESD22-A104	Ta=40°C to +125°C	850cyc	0/240
H3TRB	JESD22-A101	85°C, 85% RH, 80%bias	1008 hrs	0/240
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/240

Electrical Characteristic Summary:

List of Affected Standard Parts:

Three temperature characterization and ESD performance meet datasheet specification. Detail of Electrical characterization result is available upon request.

Part Number	Qualification Vehicle
NSR02L30NXT5G	NSR02L30NXT5G
NSR02F30NXT5G	NSR02L30NXT5G
NSR05F40NXT5G	NSR10F40NXT5G
NSR10F20NXT5G	NSR10F40NXT5G
NSR10F30NXT5G	NSR10F40NXT5G

List of Affected Customer Specific Parts:

NOTE: Please be informed that parts impacted by this PDN/PCN are Special/Customer specific parts, thus MPN & CPN info will be available to affected customers only by clicking the "Custom PCN for Selected Company Button" in the Document Analysis page of PCMS/PCN Alert